

# Soft errors considerations for low power, high reliability applications

---

IEEE Santa Clara Components,  
Packaging and Manufacturing  
Technology Chapter  
10/30/2009

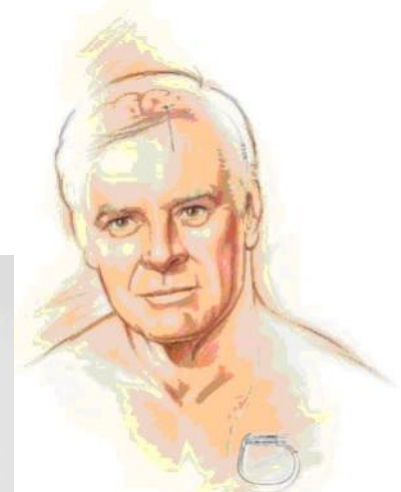
# Implanted electronic medical devices



Implantable defibrillator



Pacemaker & leads



Deep brain stimulator



Neurostimulator



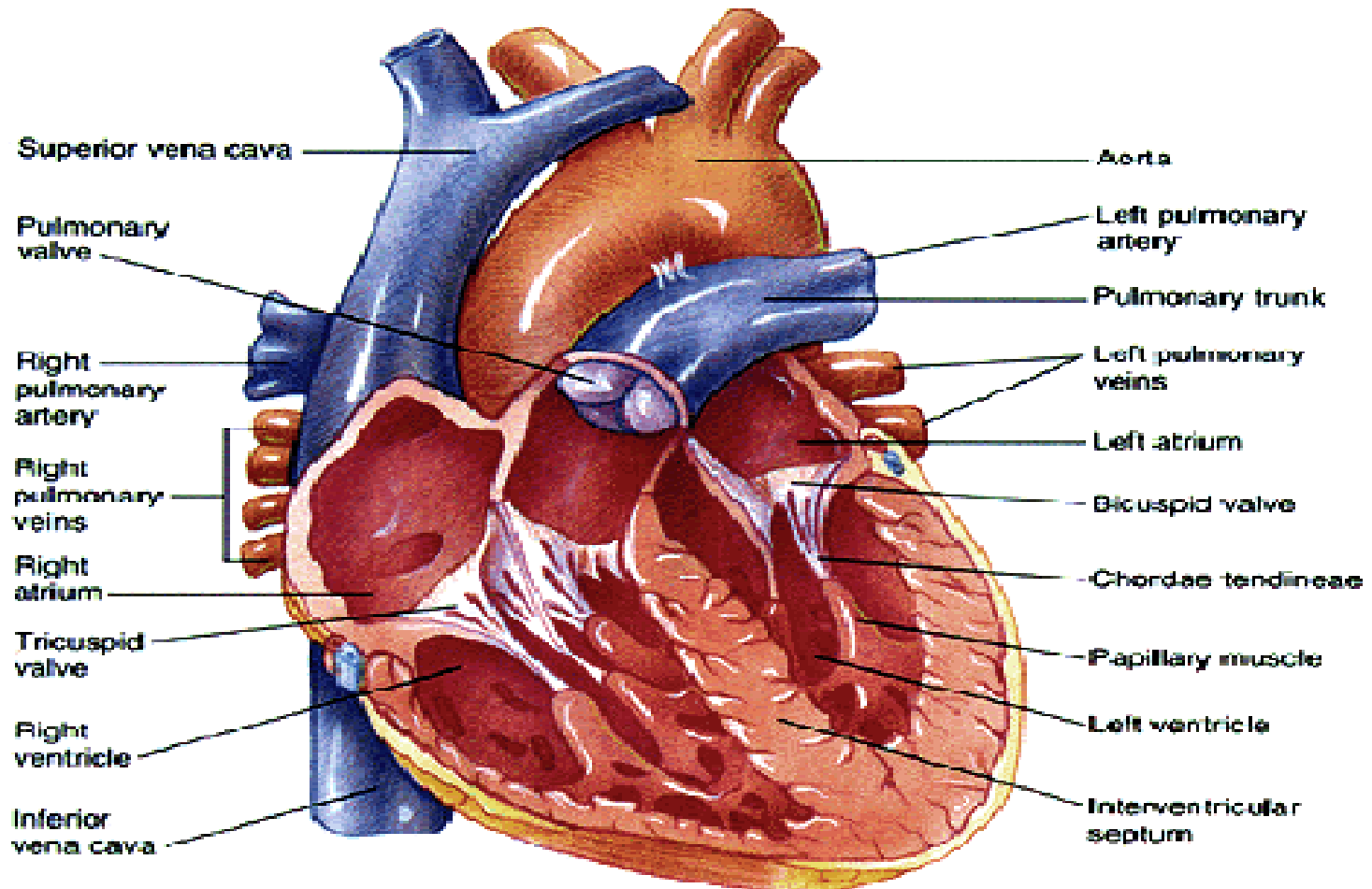
Implantable cardiac monitor



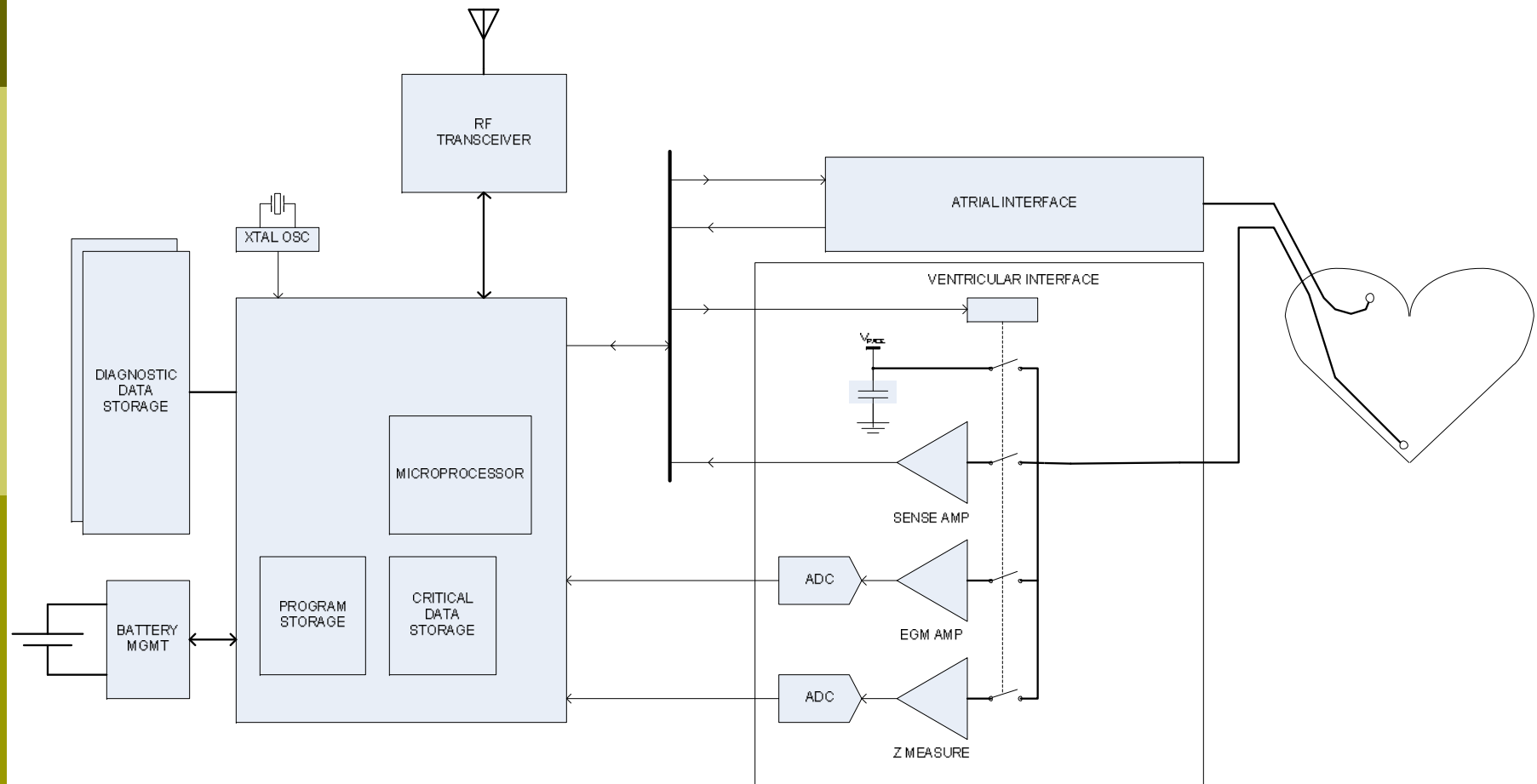
Drug pump & programmer

Cochlear implant

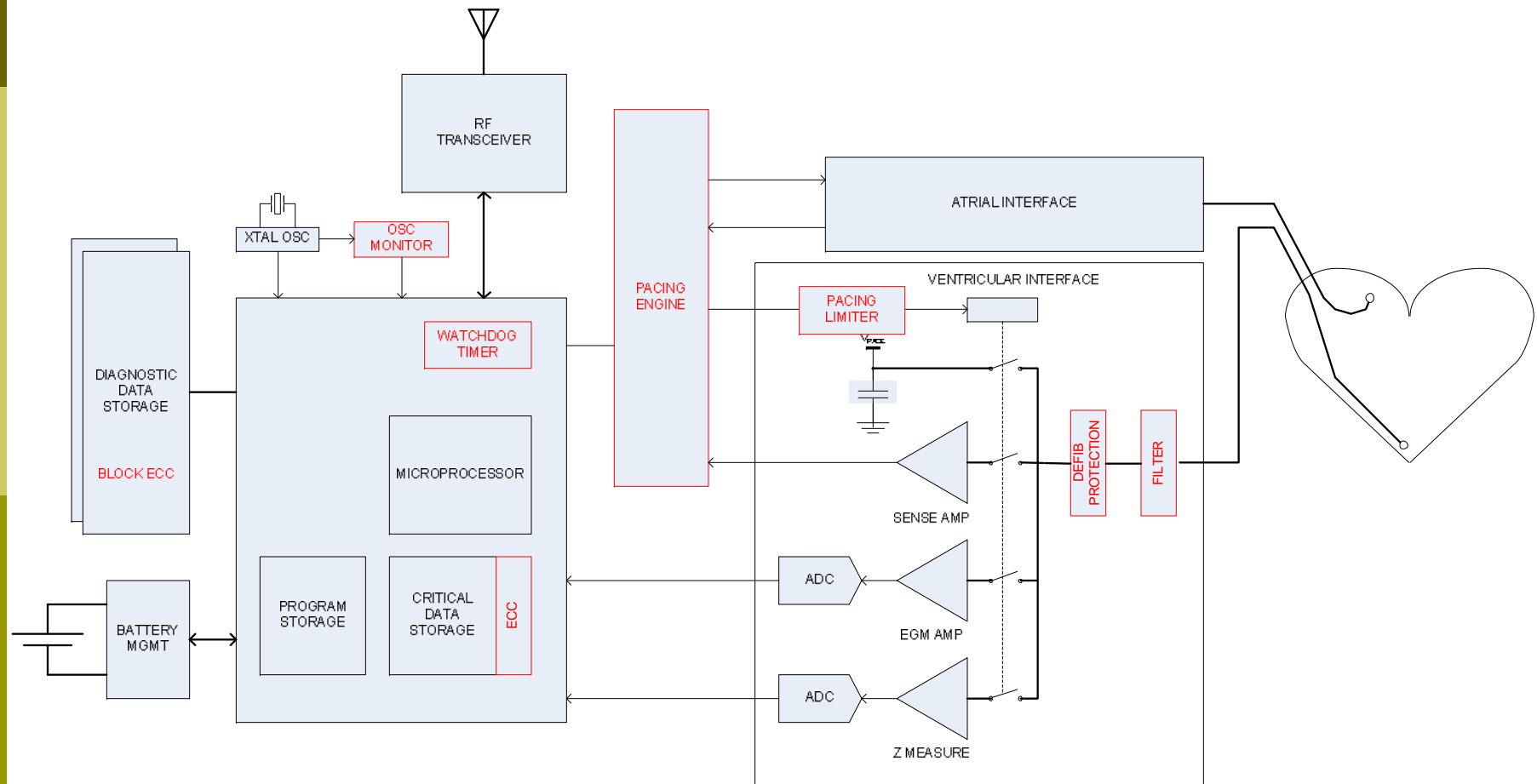
# Cardiac anatomy



# Simplified pacemaker



# Pacemaker with redundancy



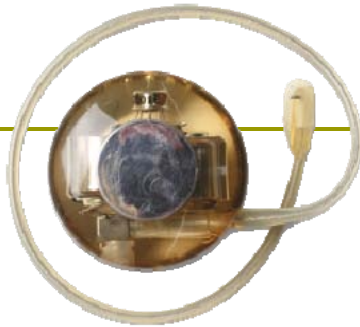
# Pacemakers Through the Years



5800

First External Pacemaker

1958



5858

Pediatric Asynchronous Pulse Generator

1970



Activitrac®

Rate response

1986



MicroMinix®

Radically smaller size

1990



Thera®

First Microprocessor-based, Mode switching

1995



EnPulse®

Full Automaticity

2004

1960

First Implantable Pacemaker

Chardack-Greatbatch



IEEE Santa Clara CPMT 2009

1979

Dual chamber rate response

Byrel®



1989

Synergist™



1991

Elite™



1998

Rate response via activity & minute ventilation

Kappa®



2006

MVP, Full Automaticity

Adapta™



# Trends & Requirements

---

- High reliability – extended service life
- No service calls or rebooting!
- Low power

# Motivations for commercial devices

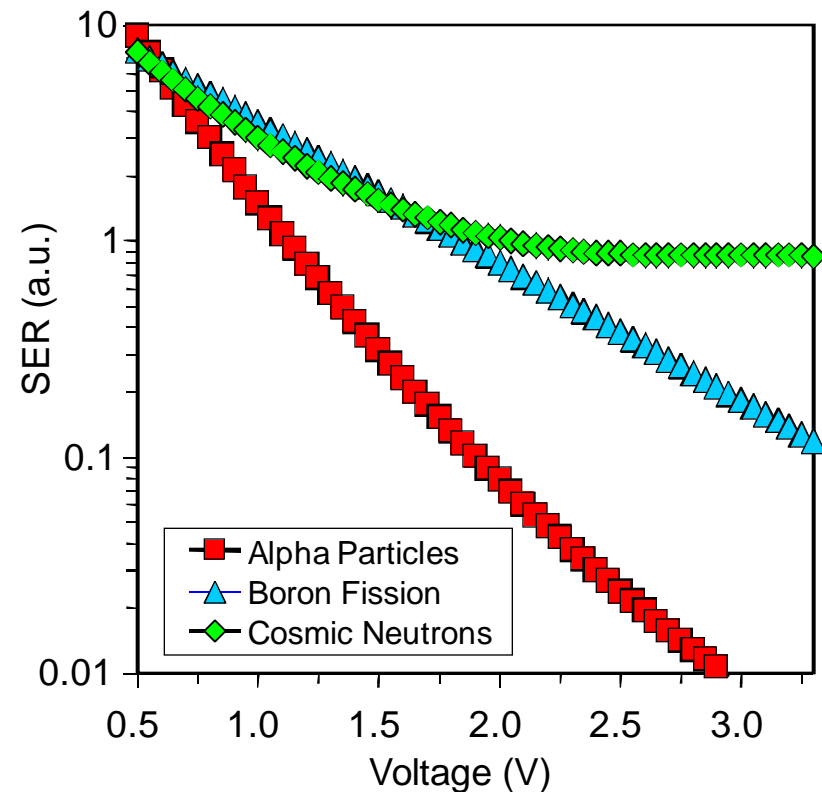
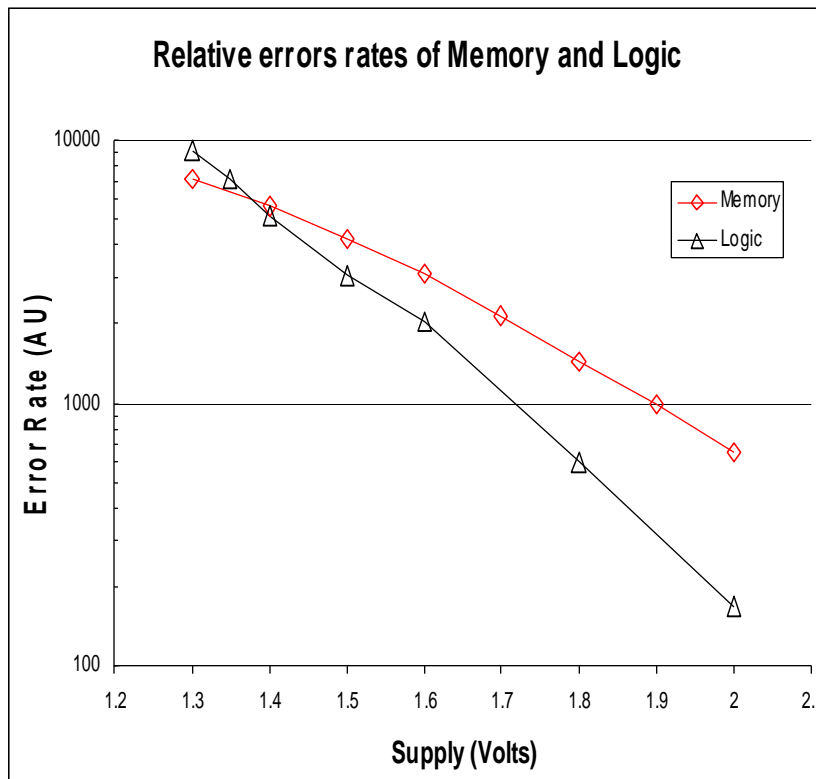
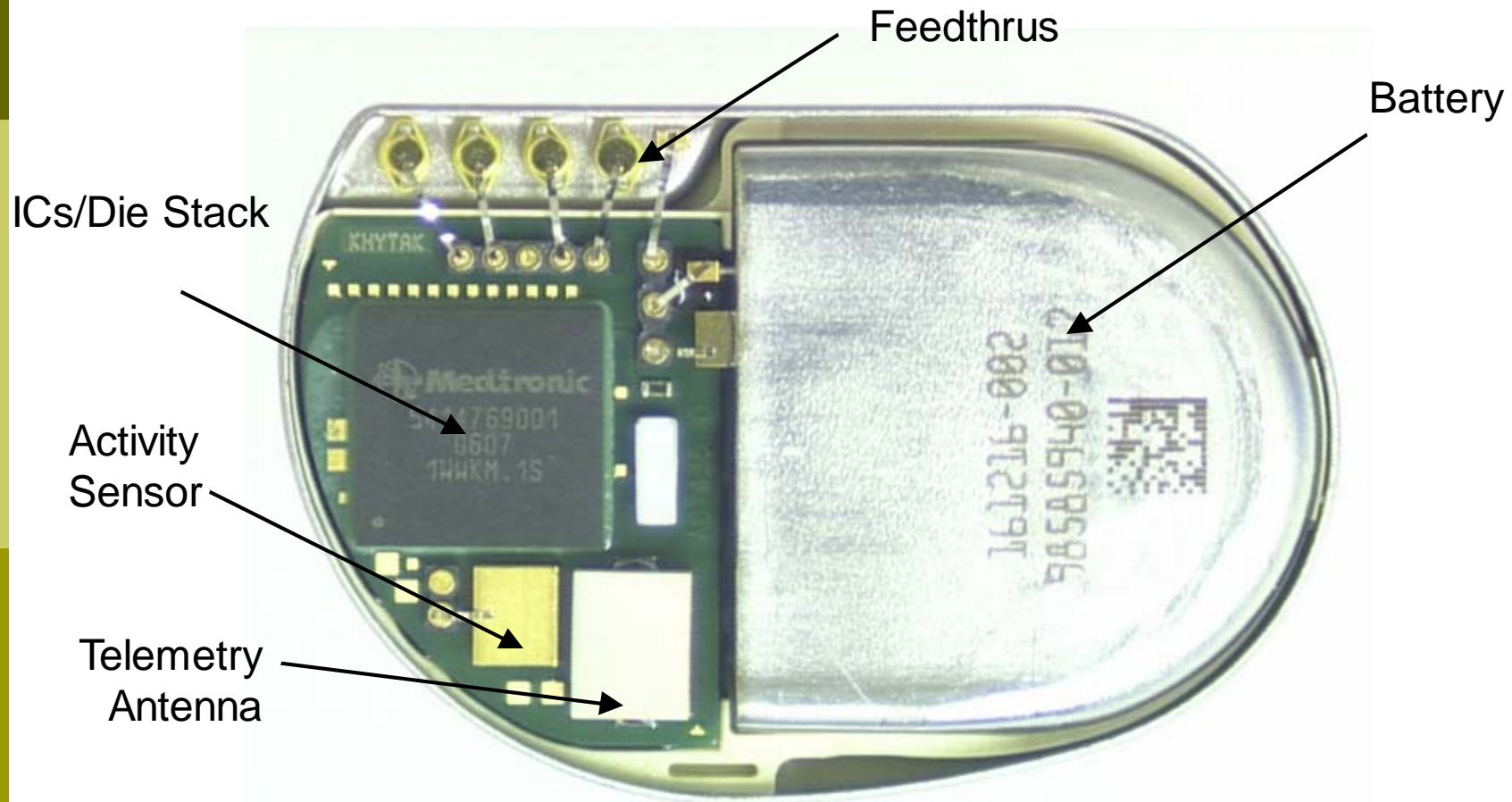


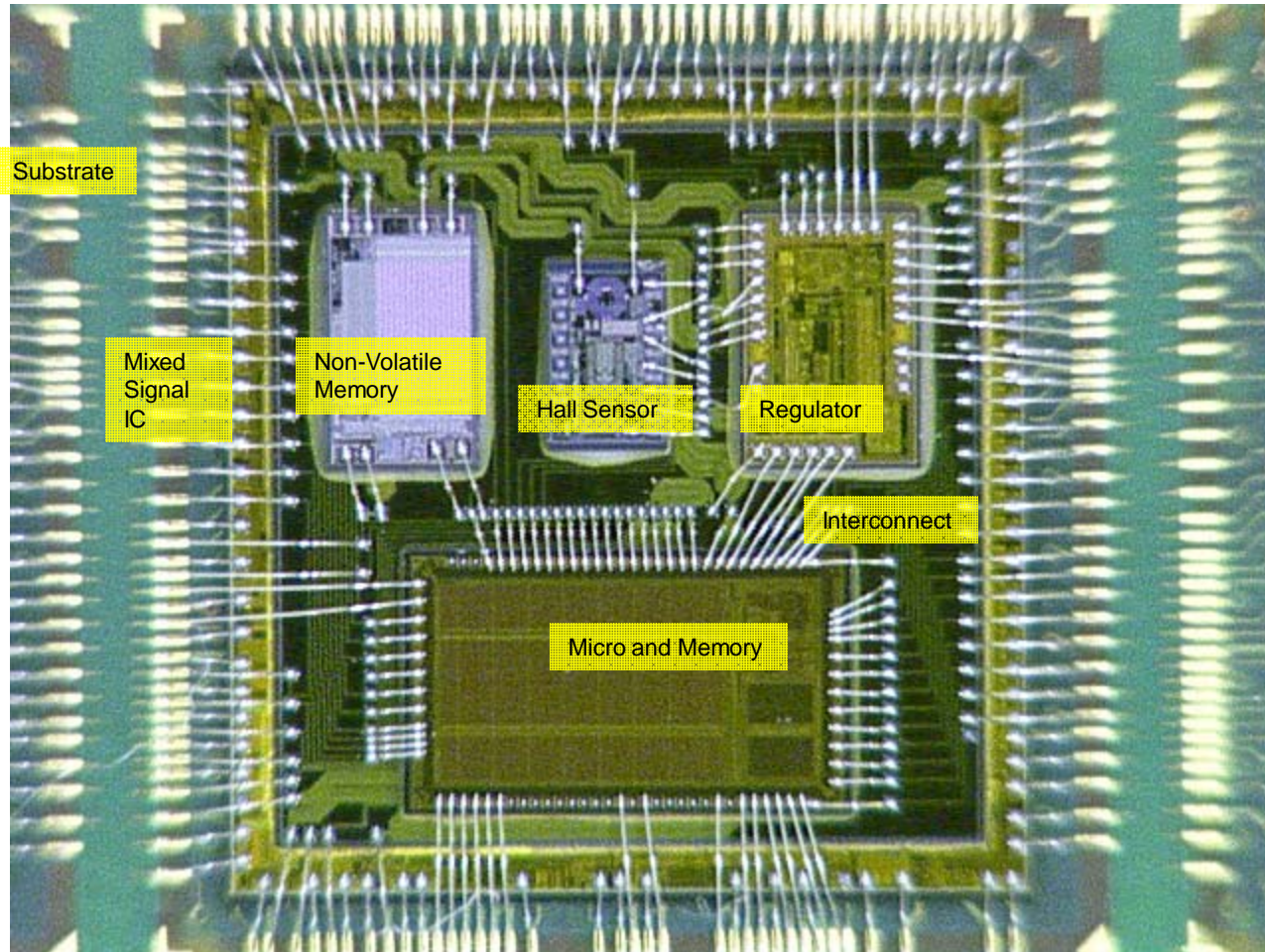
figure courtesy R. Baumann, 2008



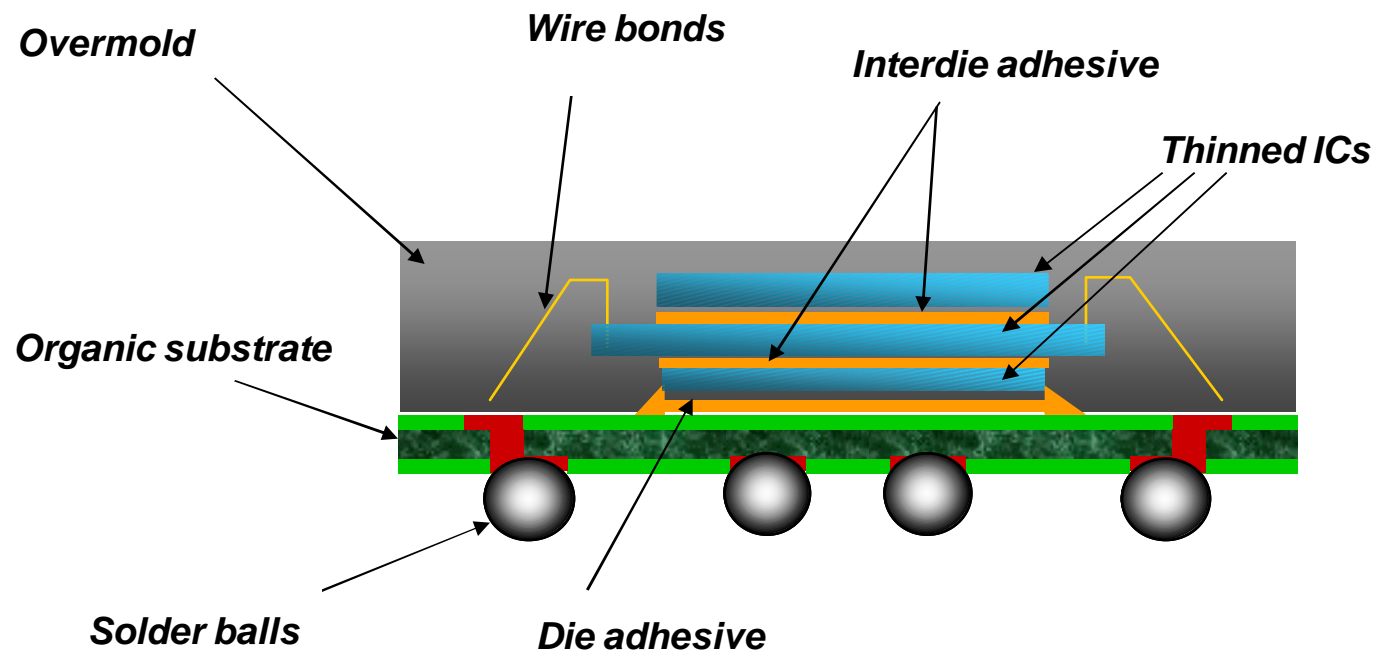
# What's Inside




# Stacked IC Technology



# Simplified Stacked IC package



# Appropriate materials selection



Technical Data Sheet

**Hysol<sup>®</sup> QMI 536**

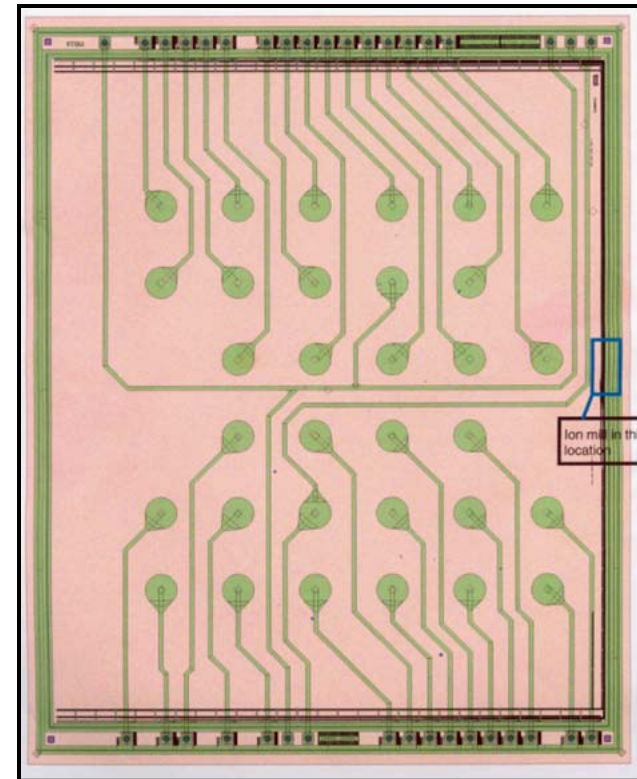
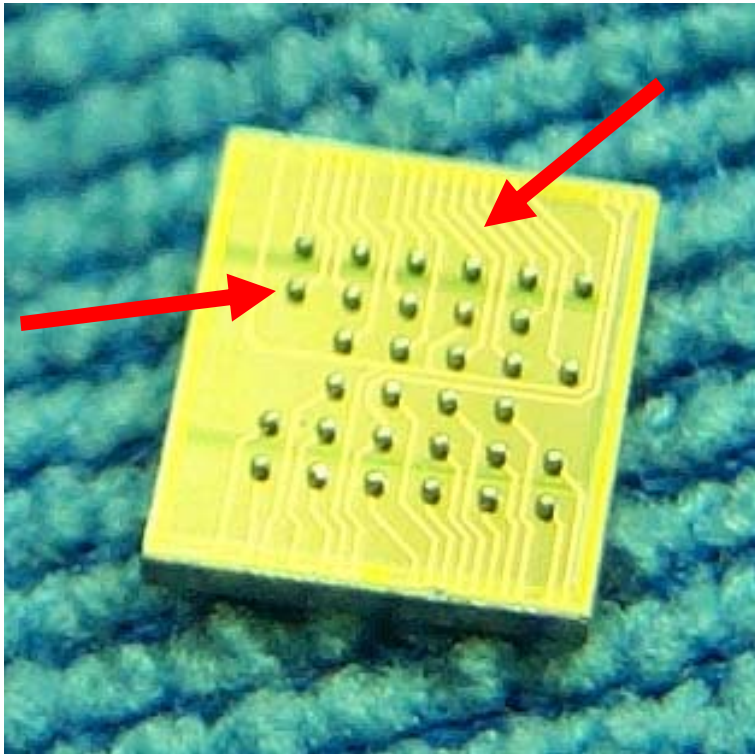
March 2004

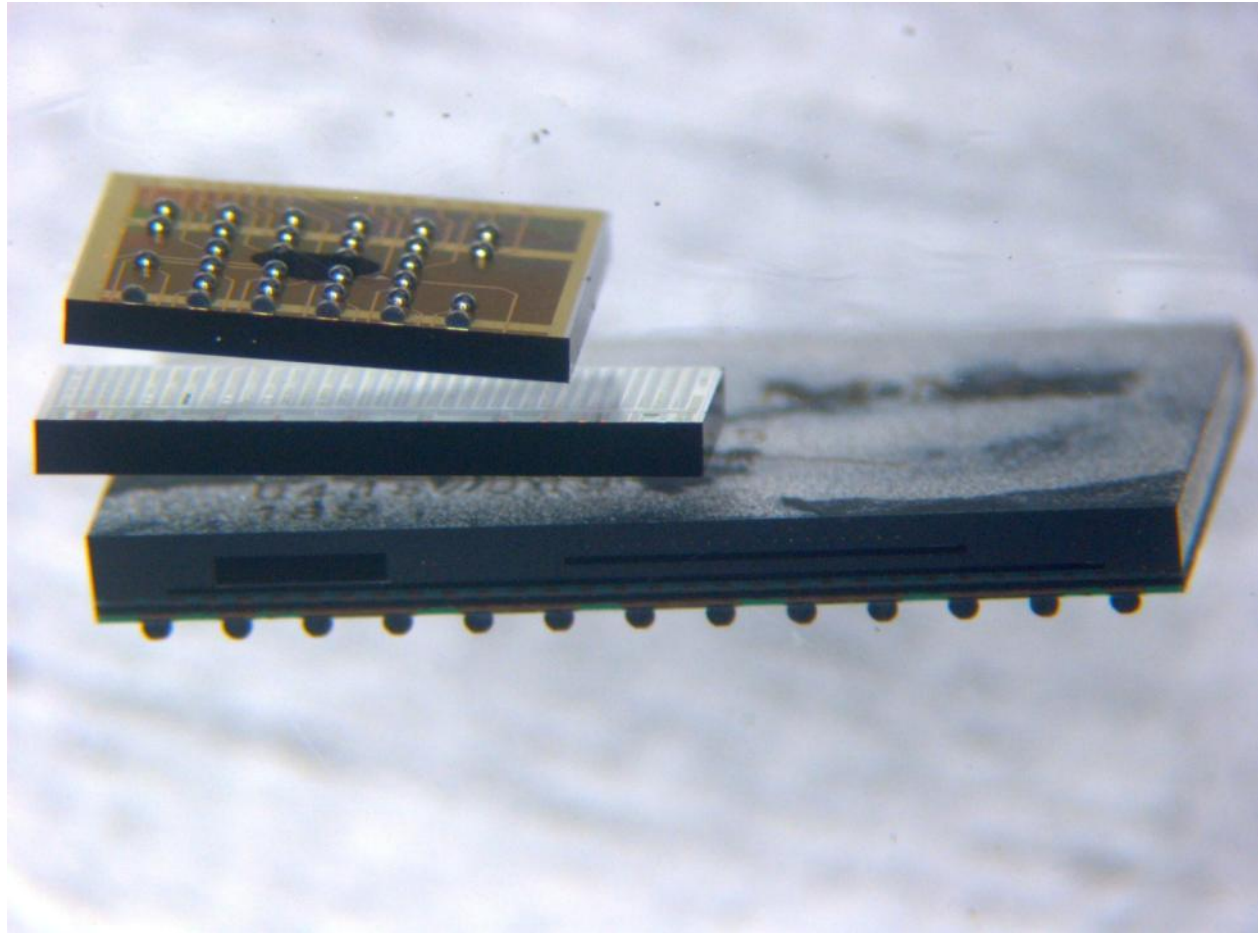
DMA Modulus @ 25°C, GPa	0.3	TM 458	<p>The data and/or range on a period be stored at</p>
DMA Modulus @ 25°C, psi	43,000		
Volume Resistivity, ohm-cm	$>10^{13}$	TM 572	<p><b>Note</b> The data and are be responsible methods v determine methods r may be ac</p>
Dielectric Constant @ 1 MHz, 25°C	2.6	TM 588	
Thermal Conductivity, W/m <sup>o</sup> K	0.3	ASTM 1461	
$\alpha$ emissions count particles/cm <sup>2</sup> /hr	0.0007	DITM 0031A	
<p>The above figures are typical material properties only and are not to be used for material specification purposes. To generate a specification</p>			

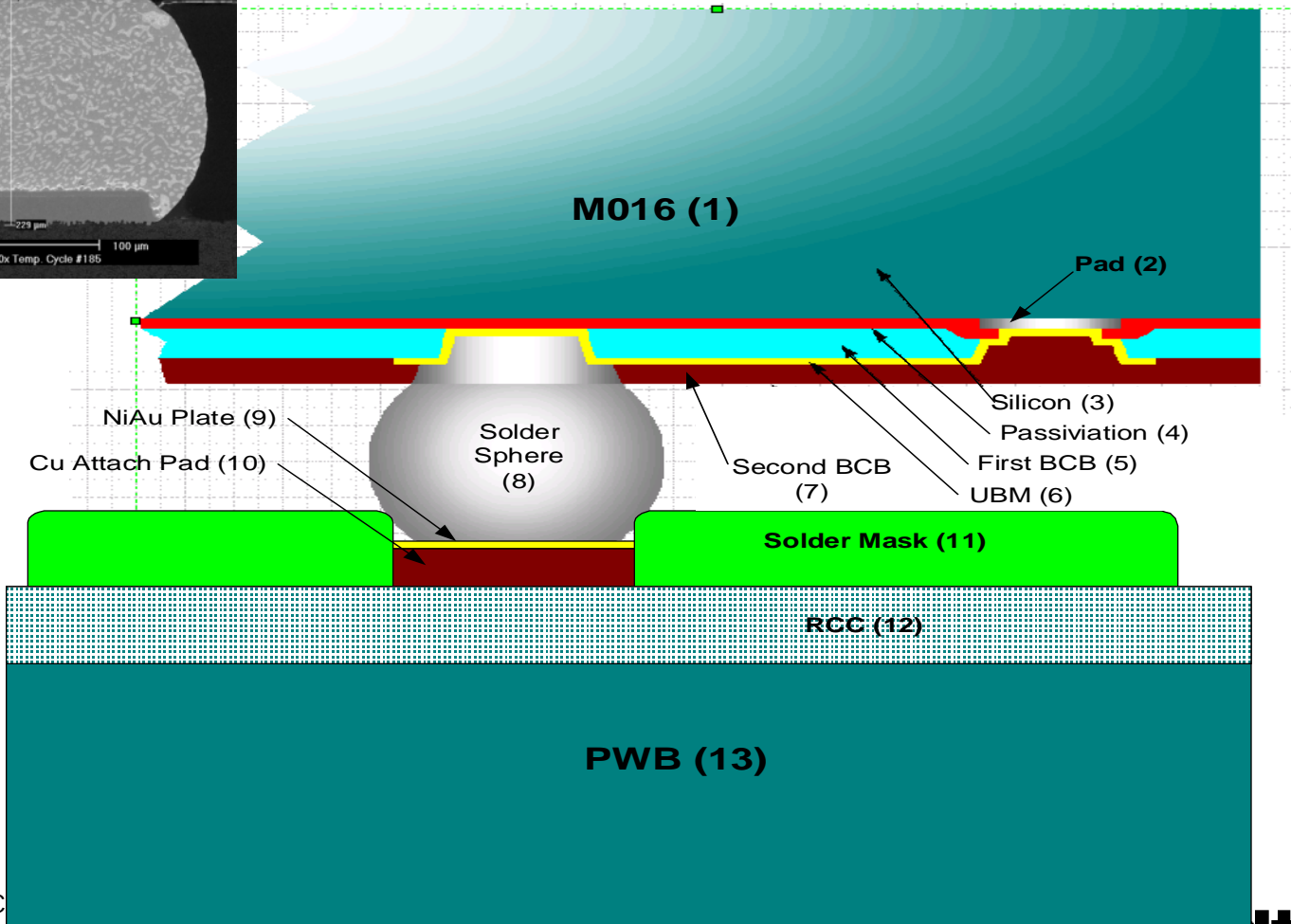
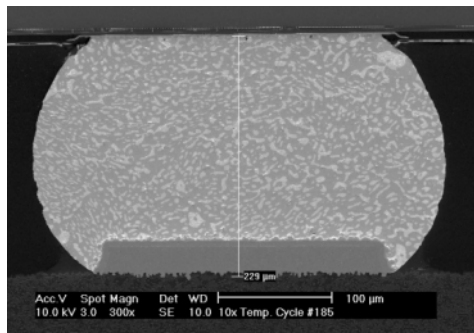
# Case Study: Chip Scale Packaging

---

# Chip scale SRAM package detail

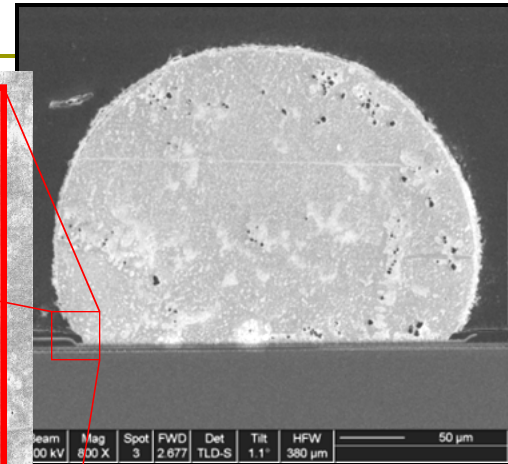
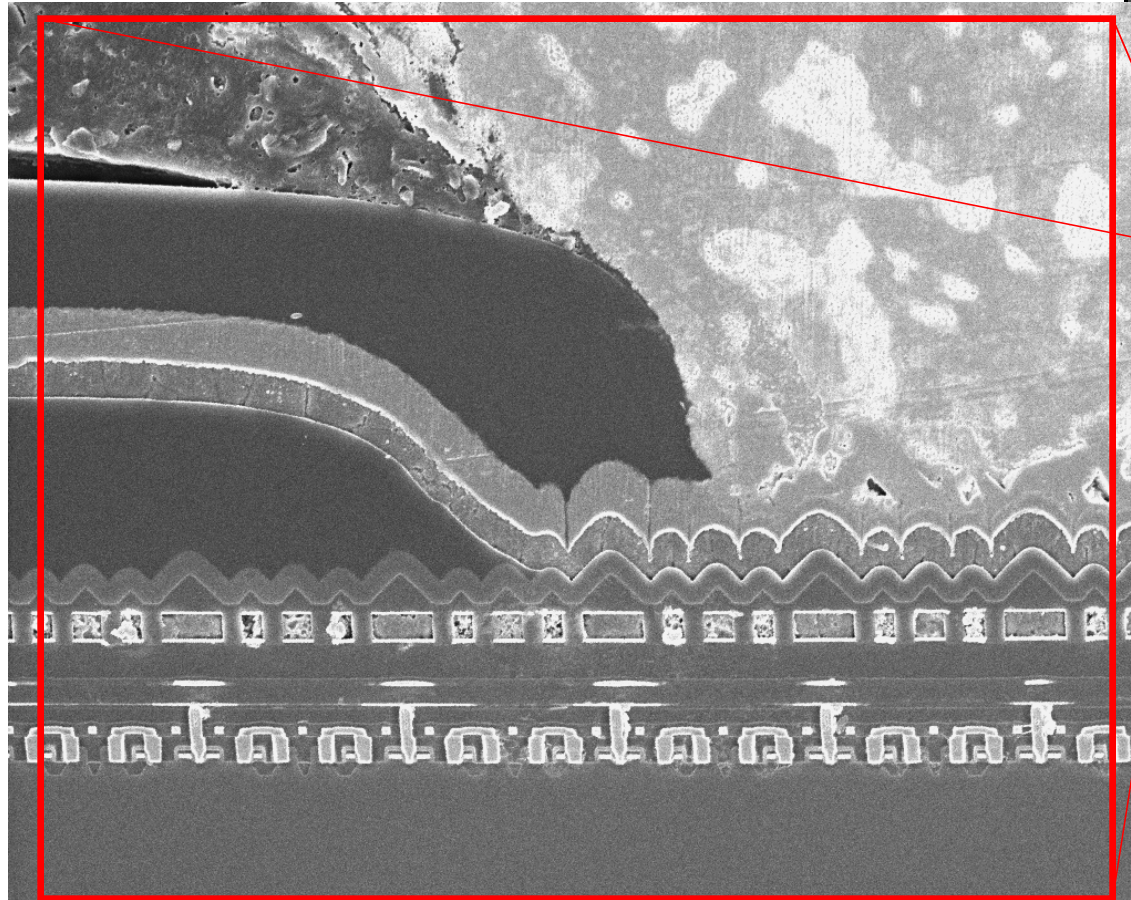






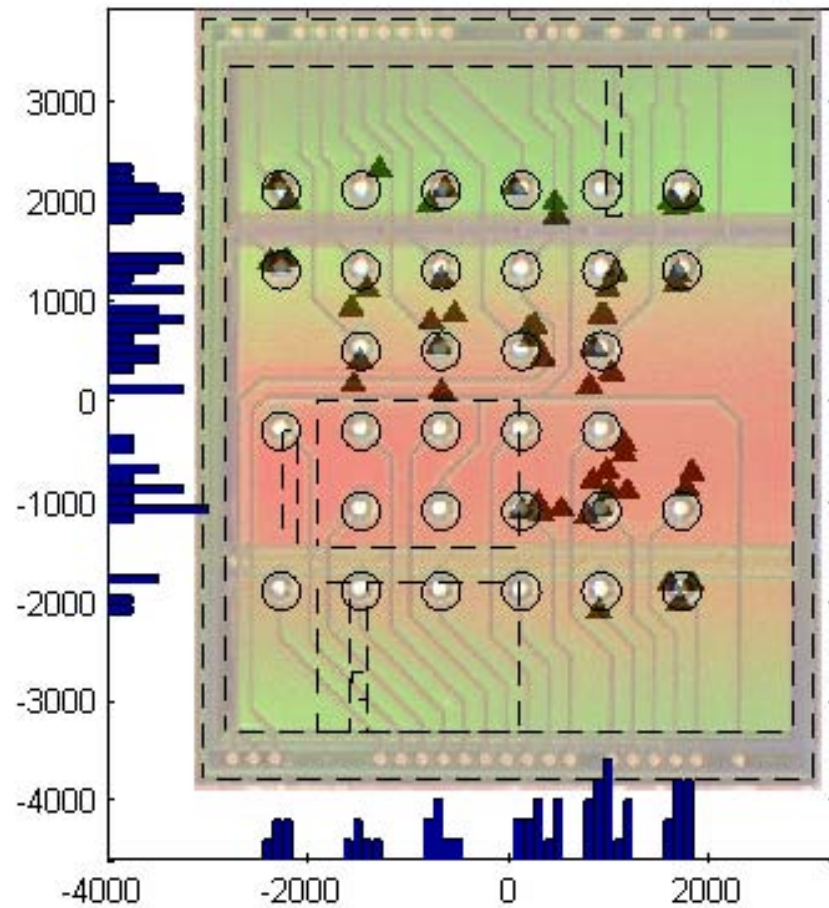


# Solder bump detail

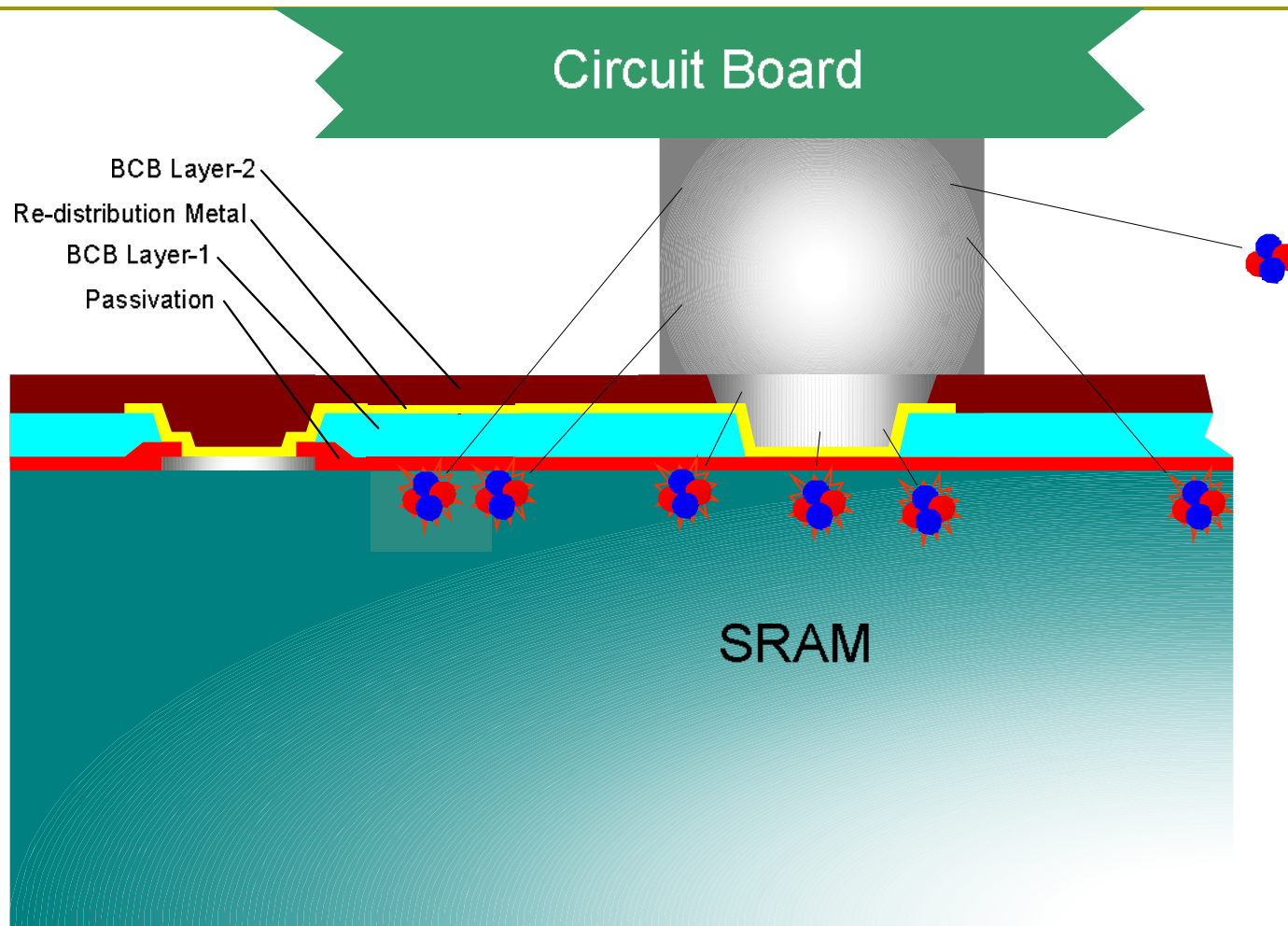


IEE	Beam	Mag	Spot	FWD	Det	Tilt	HFV	5 $\mu$ m
	5.00 kV	10.0 kX	2	2.674	TLD-S	1.1°	30.4 $\mu$ m	

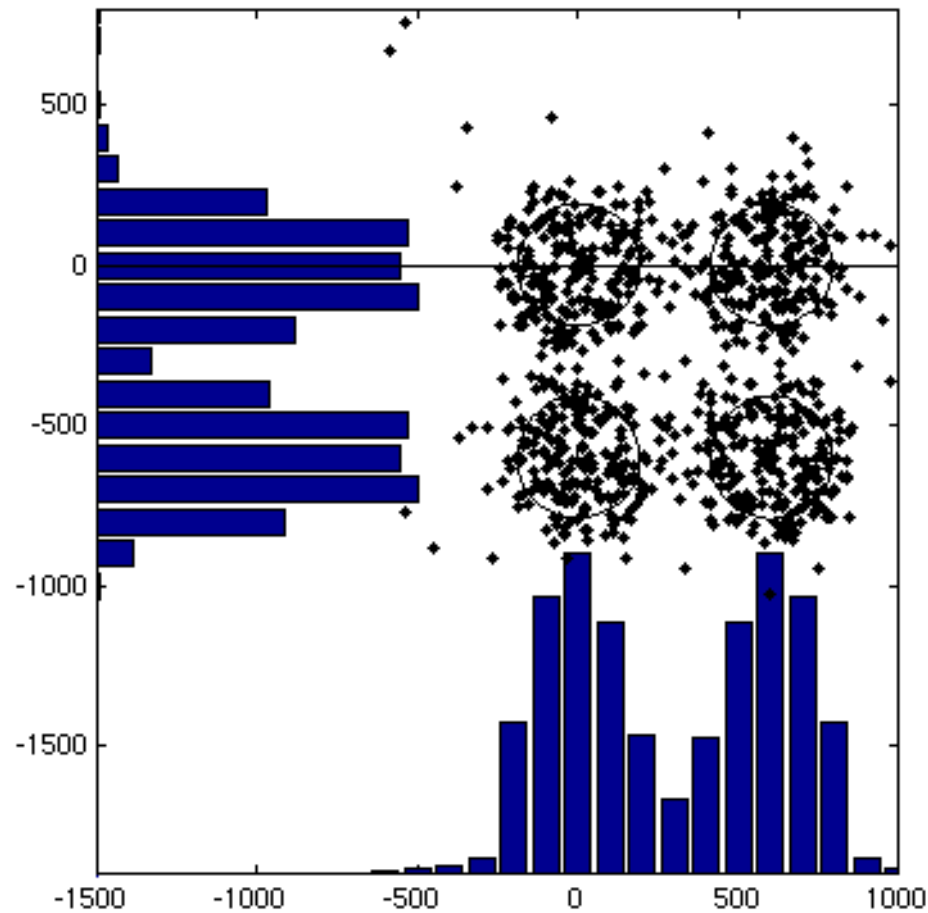
# Physical error mapping



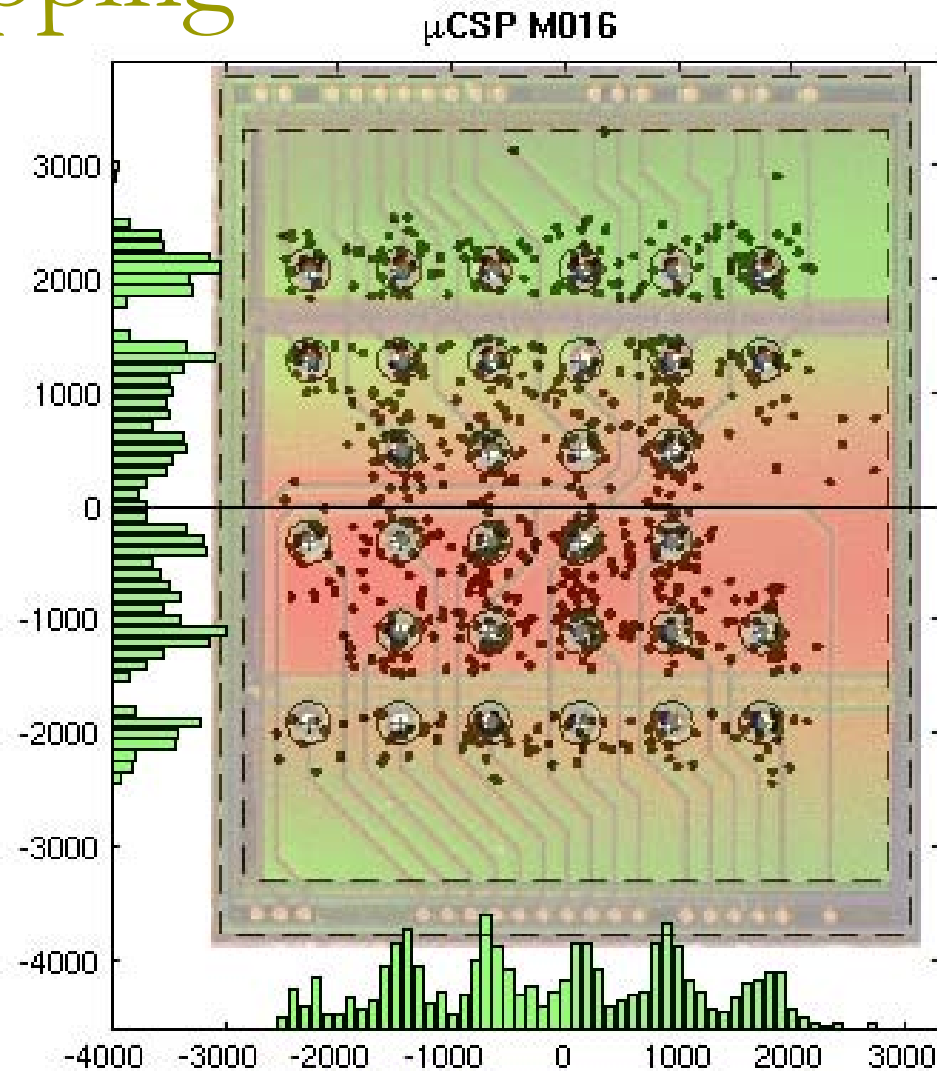
# $\alpha$ -particles from solder balls



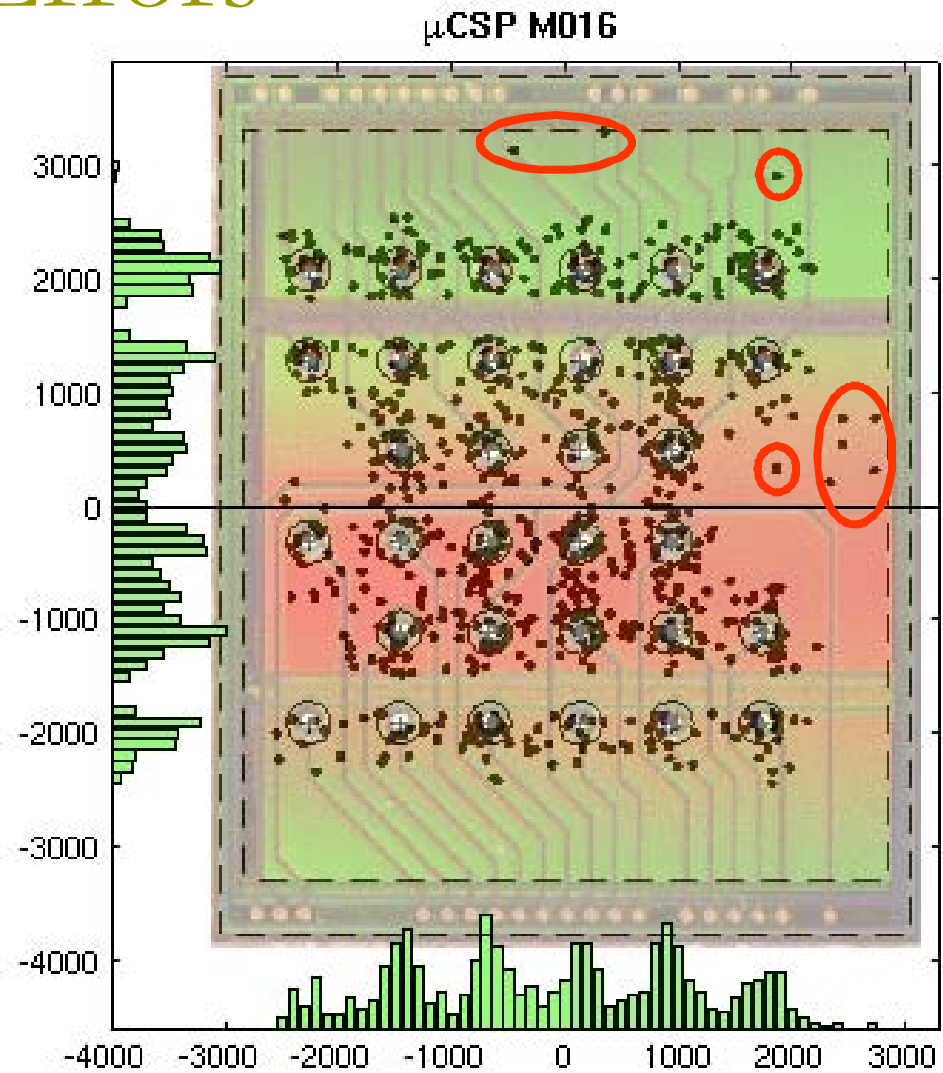
# Soft-error range modeling



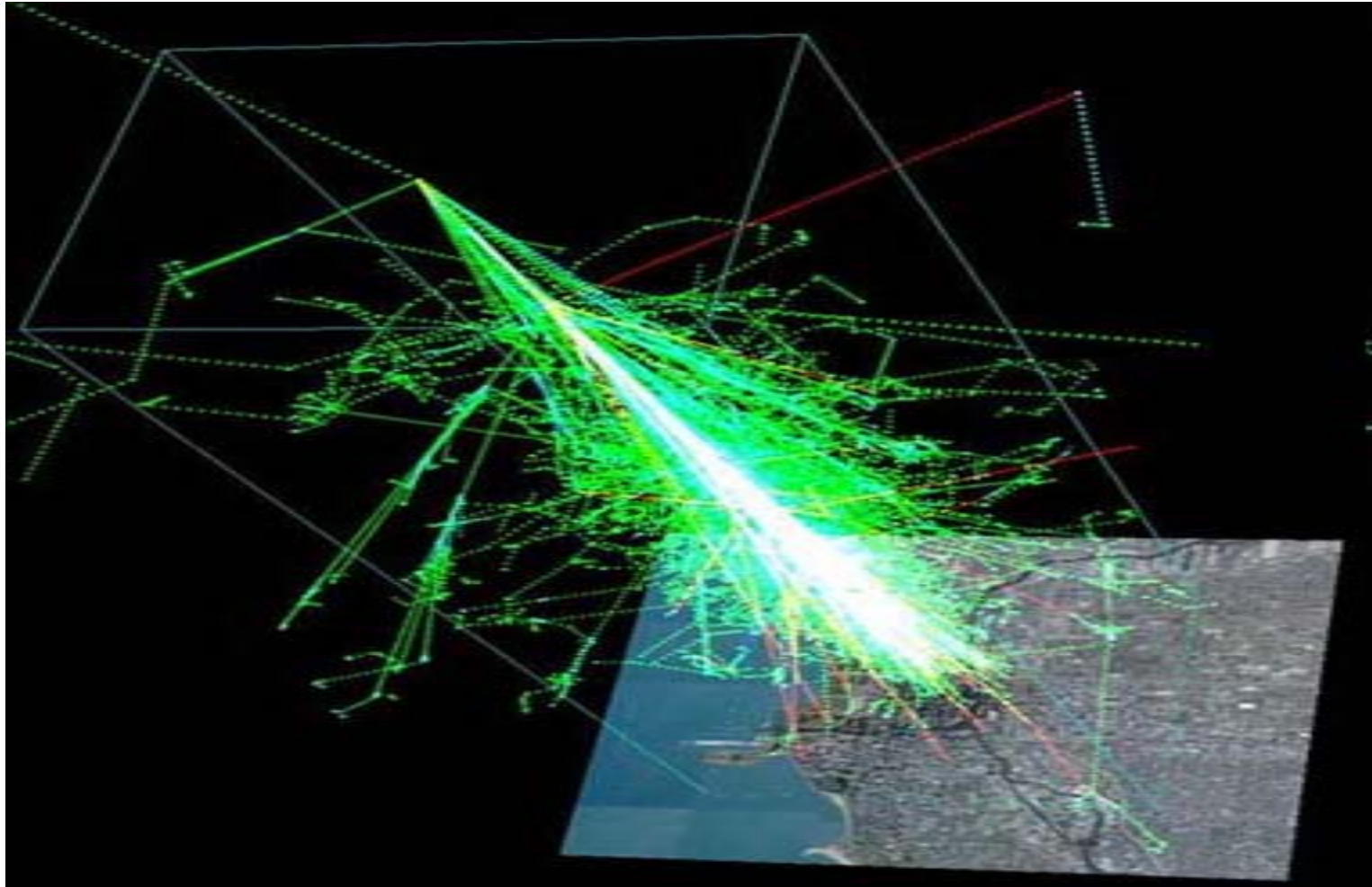
# Error mapping



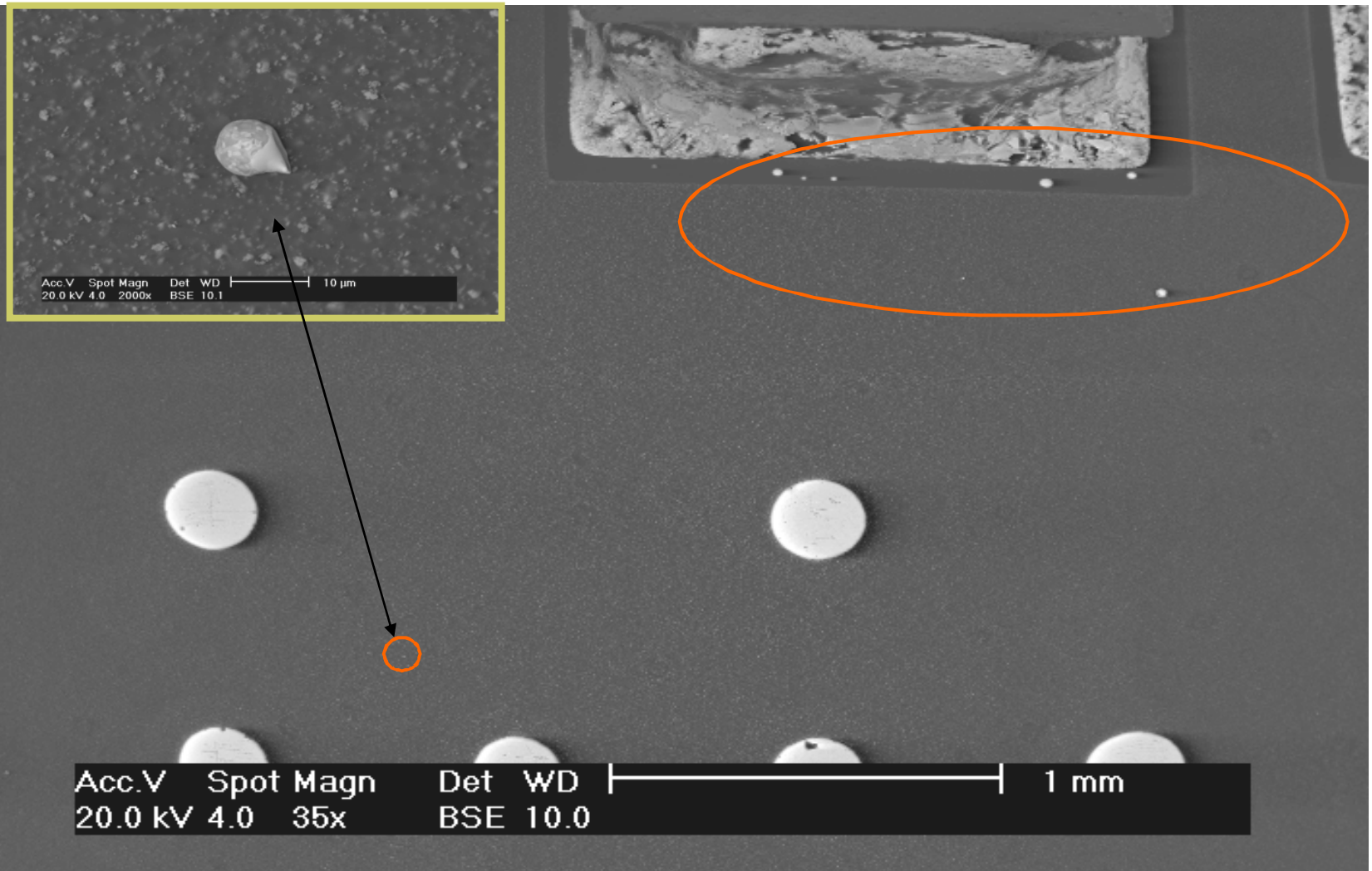
# Residual Errors



# Cosmic rays?



# Solder spits?



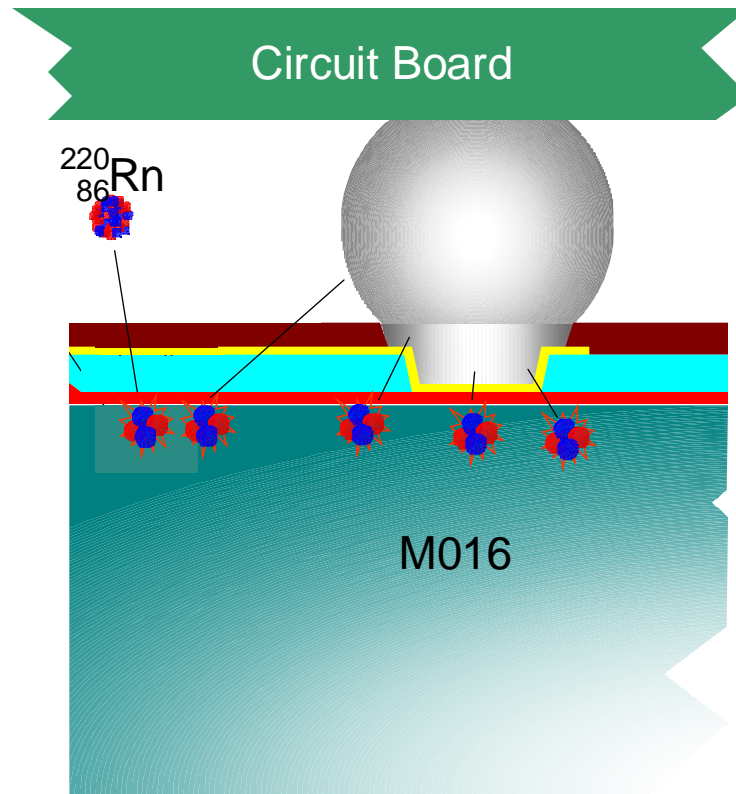
IEEE S...

Data and photographs courtesy of Mark Henschel



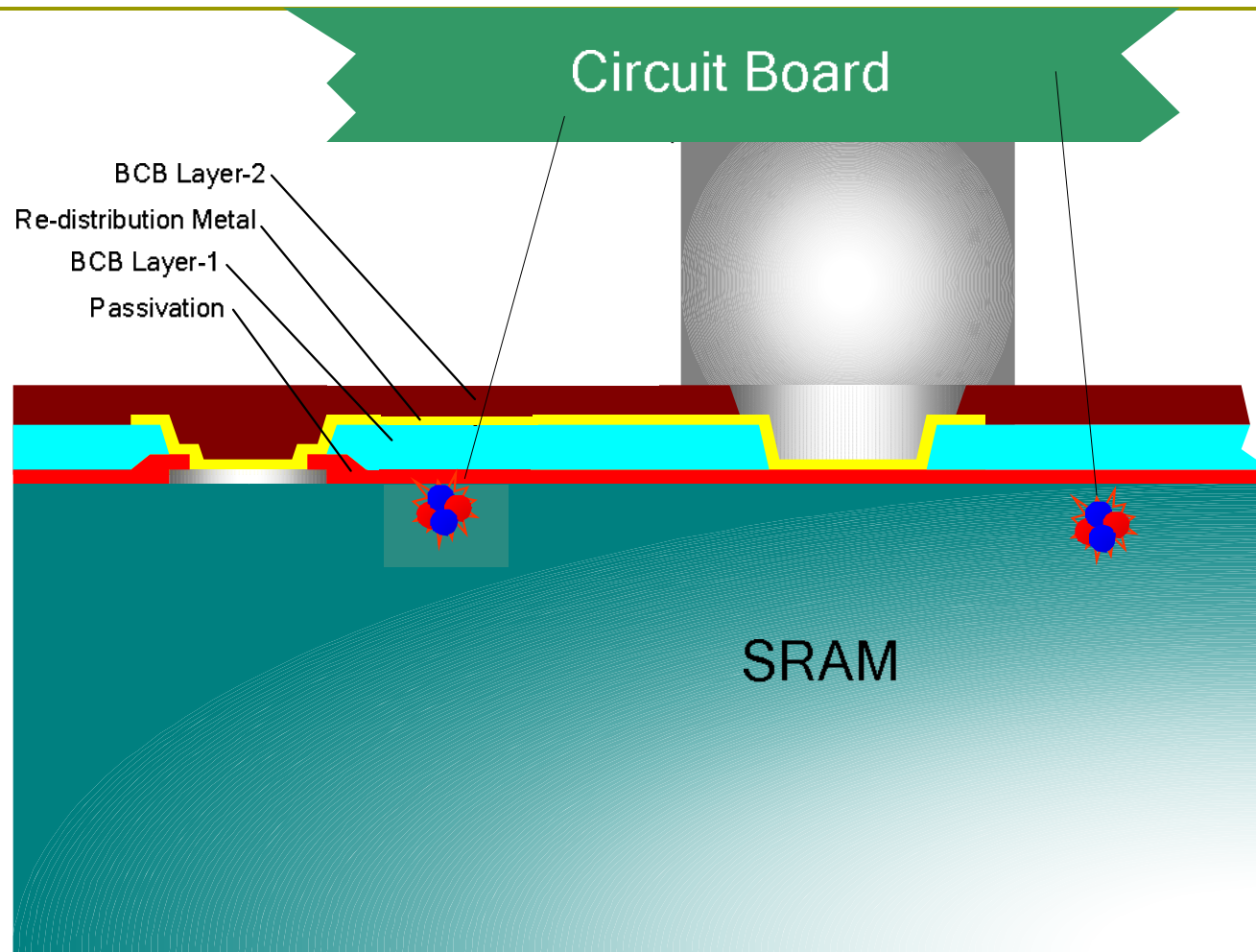


# Radon in the air?

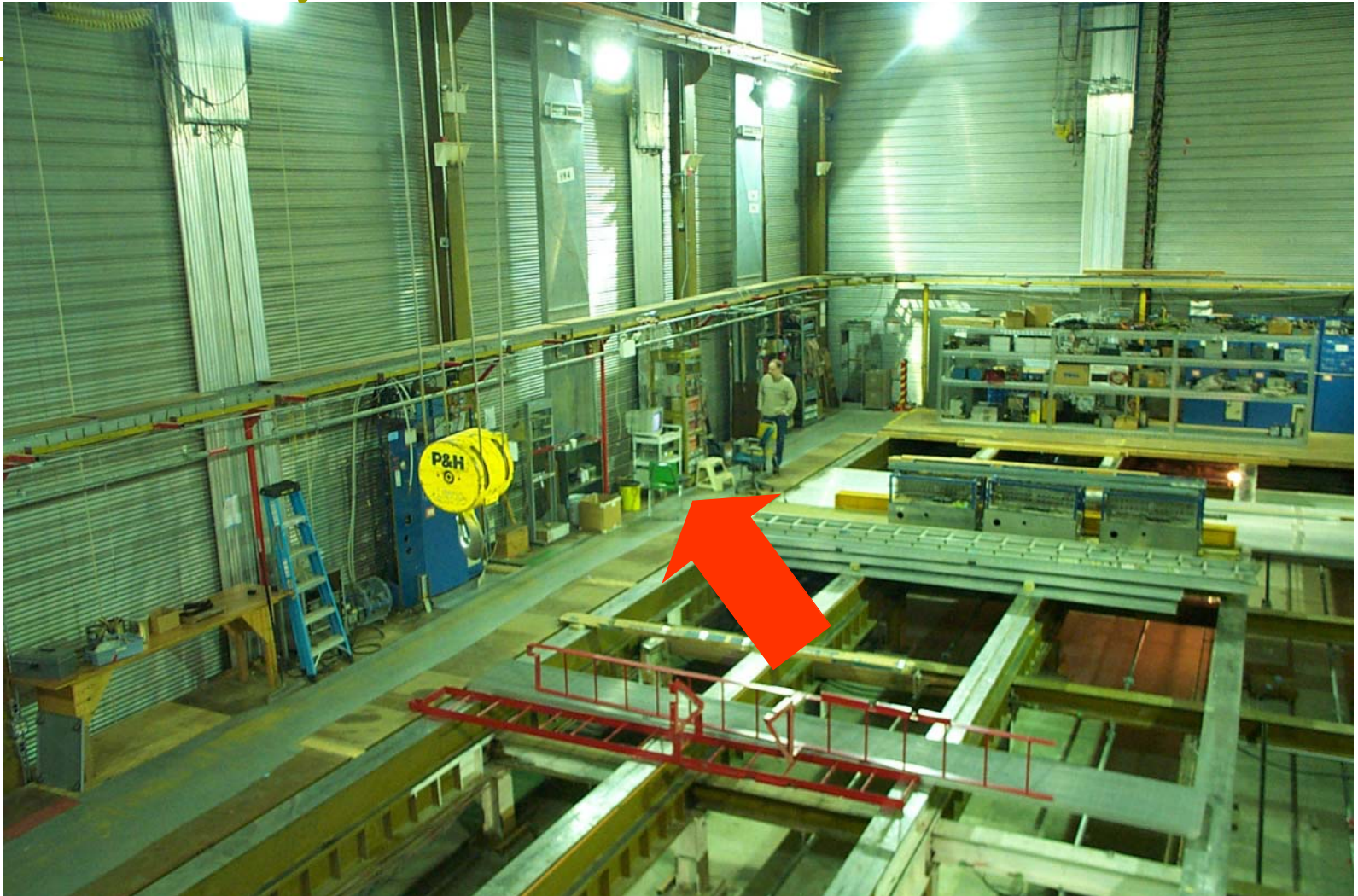


- Radon is an  $\alpha$  emitter
- 10 pCi/liter would explain excess errors
- EPA limit for homes is 4 pCi/liter

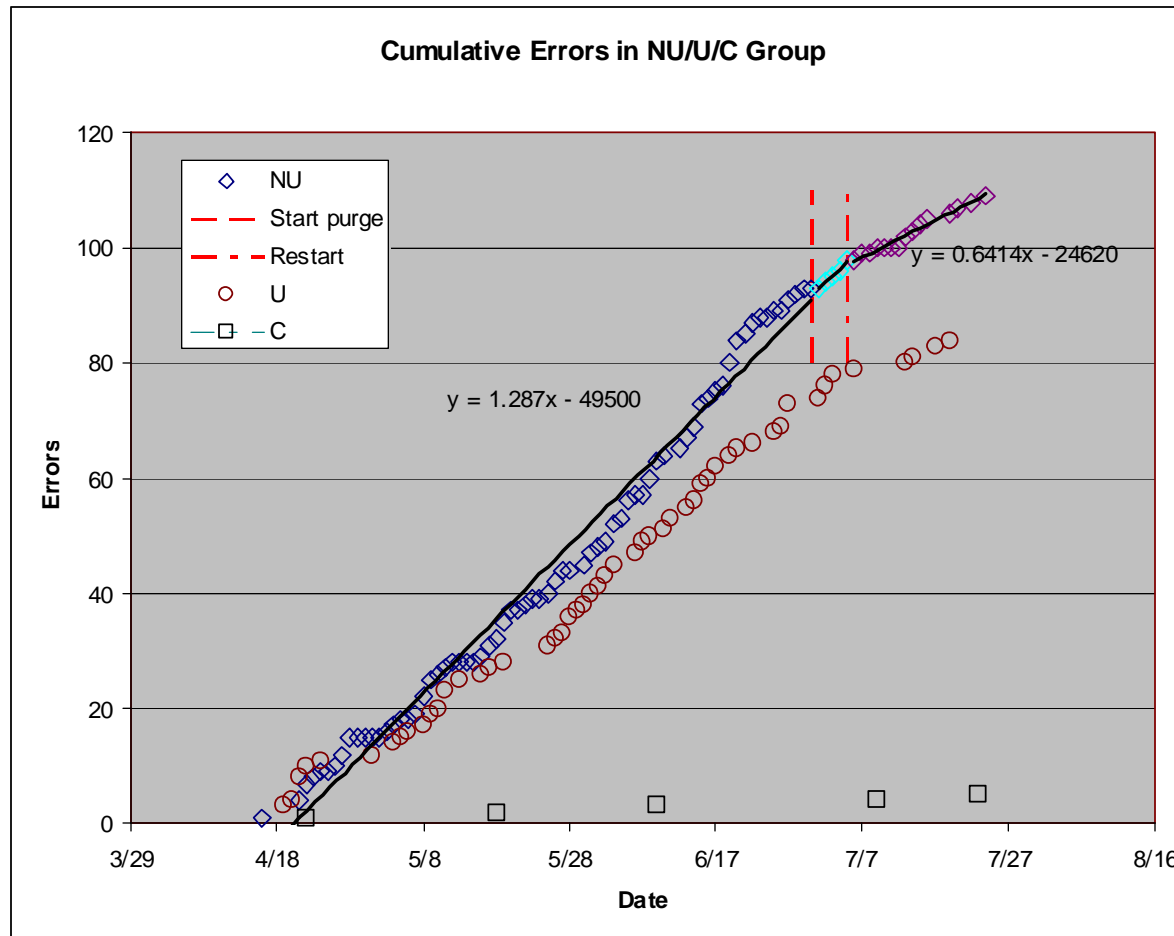
# $\alpha$ -particles from circuit board



# Bulk Memory Test at Soudan Iron Mine



# Soudan Iron Mine Data




# Error rate summary

---

Experiment	Error Rate (a.u./Mbit)
Original spheres, no underfill	100
Low-alpha spheres, no underfill	2
Low-alpha spheres, clean underfill	0.5

# Excellent materials are available...



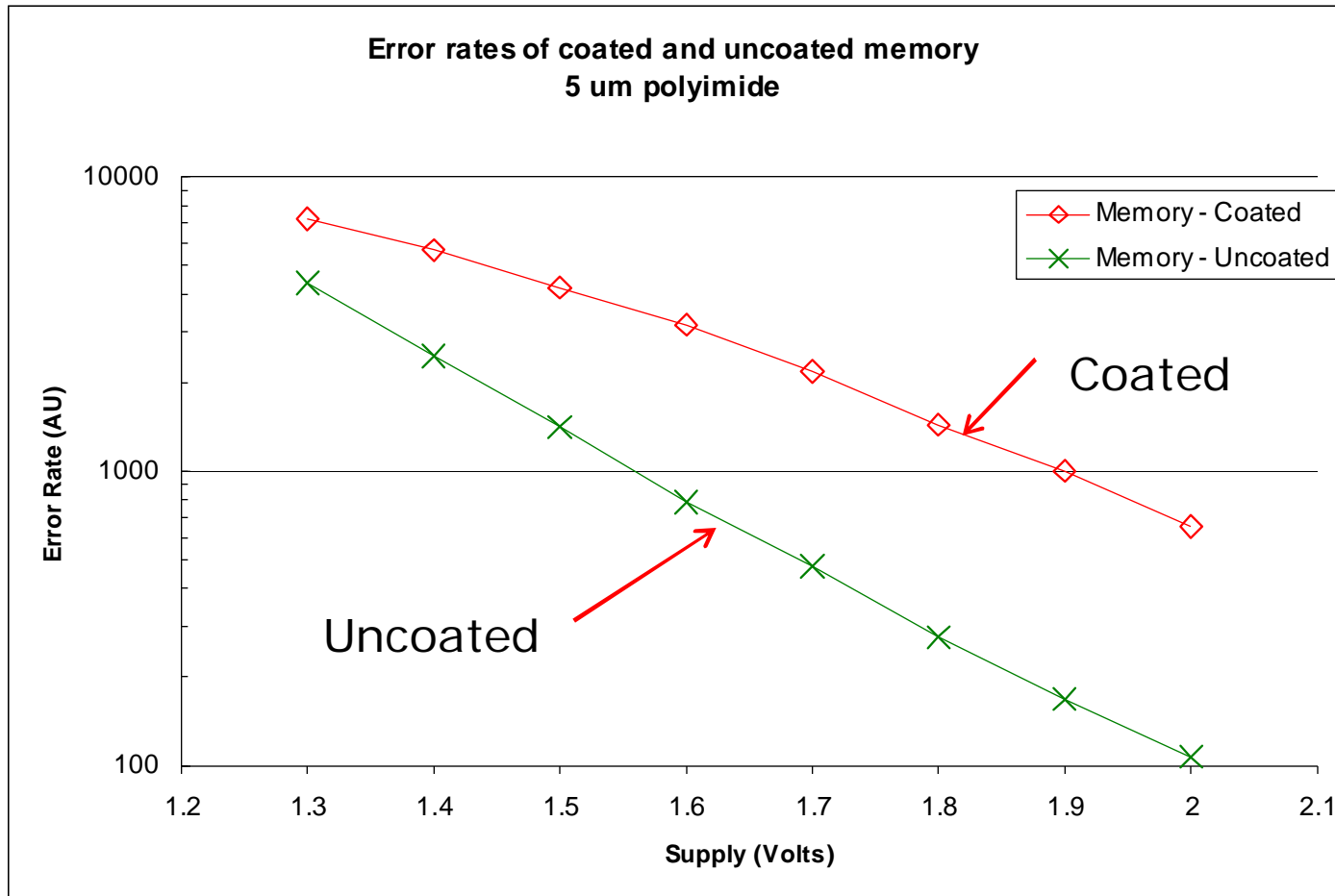
Technical Data Sheet

**Hysol<sup>®</sup> QMI 536**

March 2004

DMA Modulus @ 25°C, GPa	0.3	TM 458	<p>The data and/or range on a period be stored at</p> <p>Stack Handling</p>
DMA Modulus @ 25°C, psi	43,000		
Volume Resistivity, ohm-cm	$>10^{13}$	TM 572	<p><b>Note</b></p> <p>The data and are be responsible methods v determine methods r may be ac</p>
Dielectric Constant @ 1 MHz, 25°C	2.6	TM 588	
Thermal Conductivity, W/m <sup>o</sup> K	0.3	ASTM 1461	
$\alpha$ emissions count particles/cm <sup>2</sup> /hr	0.0007	DITM 0031A	
<p>The above figures are typical material properties only and are not to be used for material specification purposes. To generate a specification</p>			

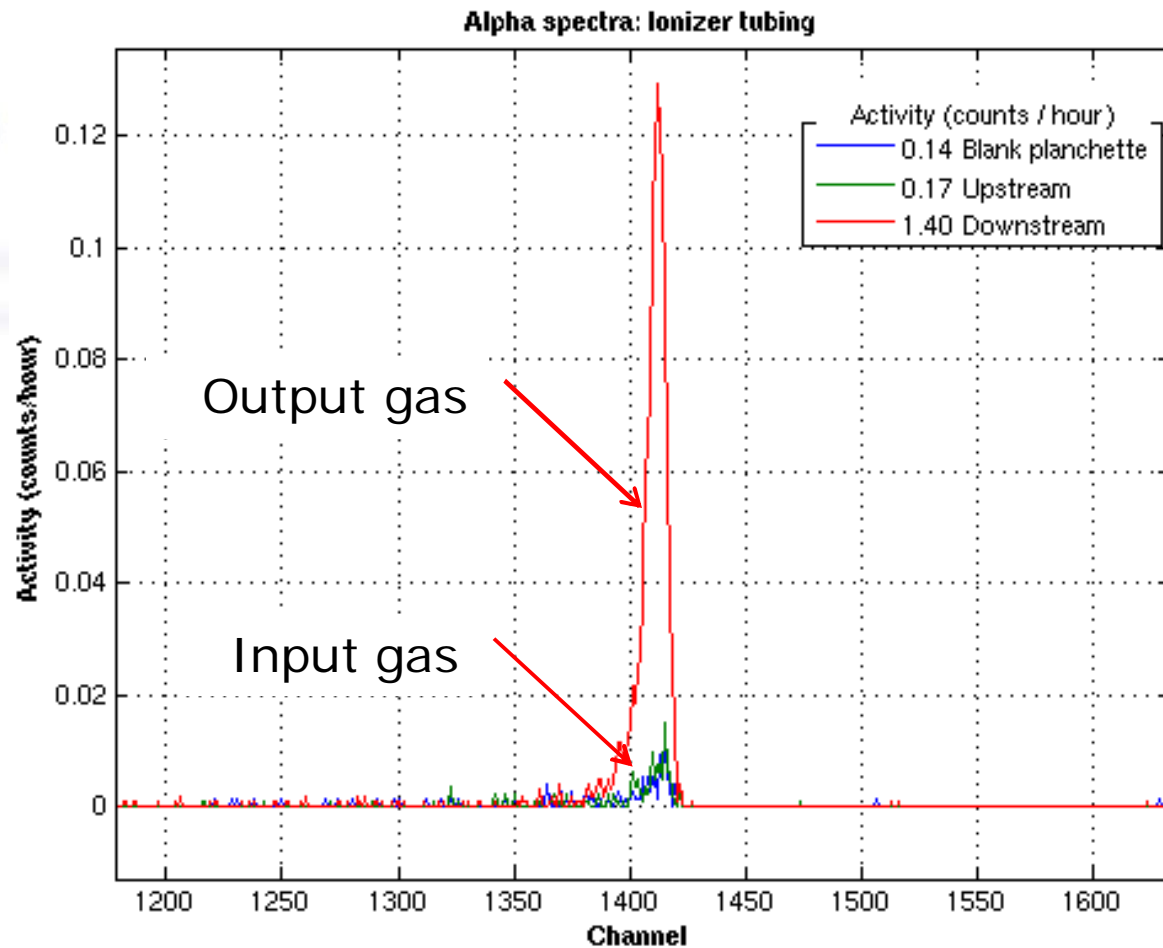
# Low- $\alpha$ coatings



# Manufacturing process will dominate

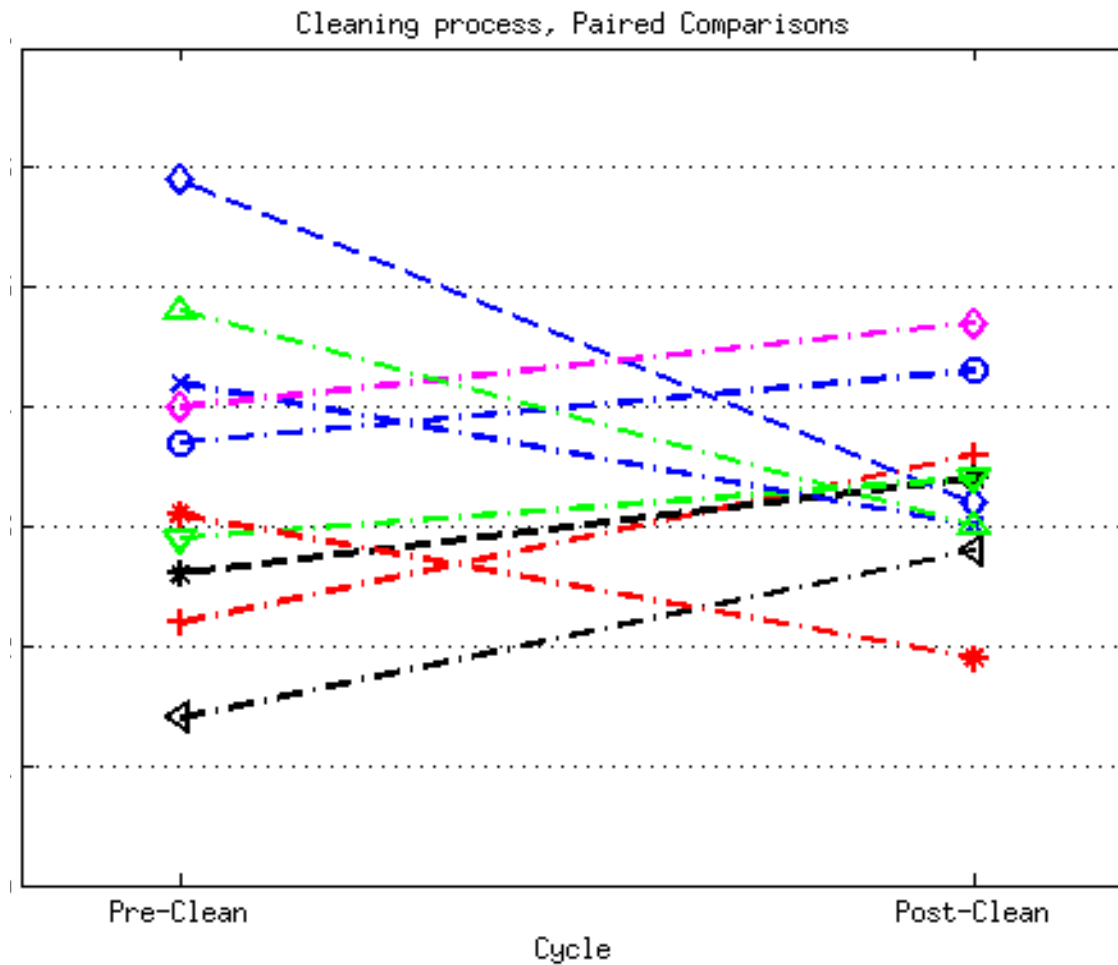


$^{210}\text{Po}$  ionizer for static control





# Low- $\alpha$ manufacturing



# Conclusions

---

- Commercial trends are making SEU an everyone's problem.
  - Packaging
  - Feature sizes
  - Supply voltages
  - System complexity
- Package engineering is critical to success.
- High quality packaging materials are available...

*... but ...*

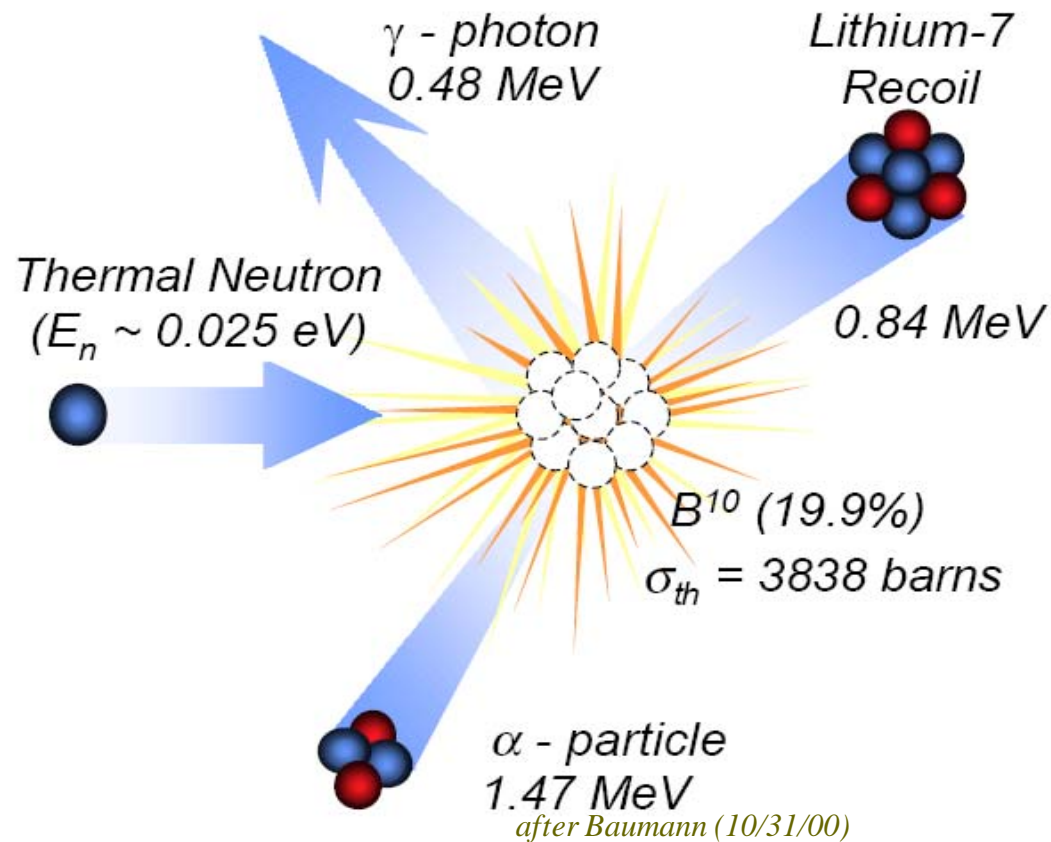
... the process determines alpha performance.

# Questions?

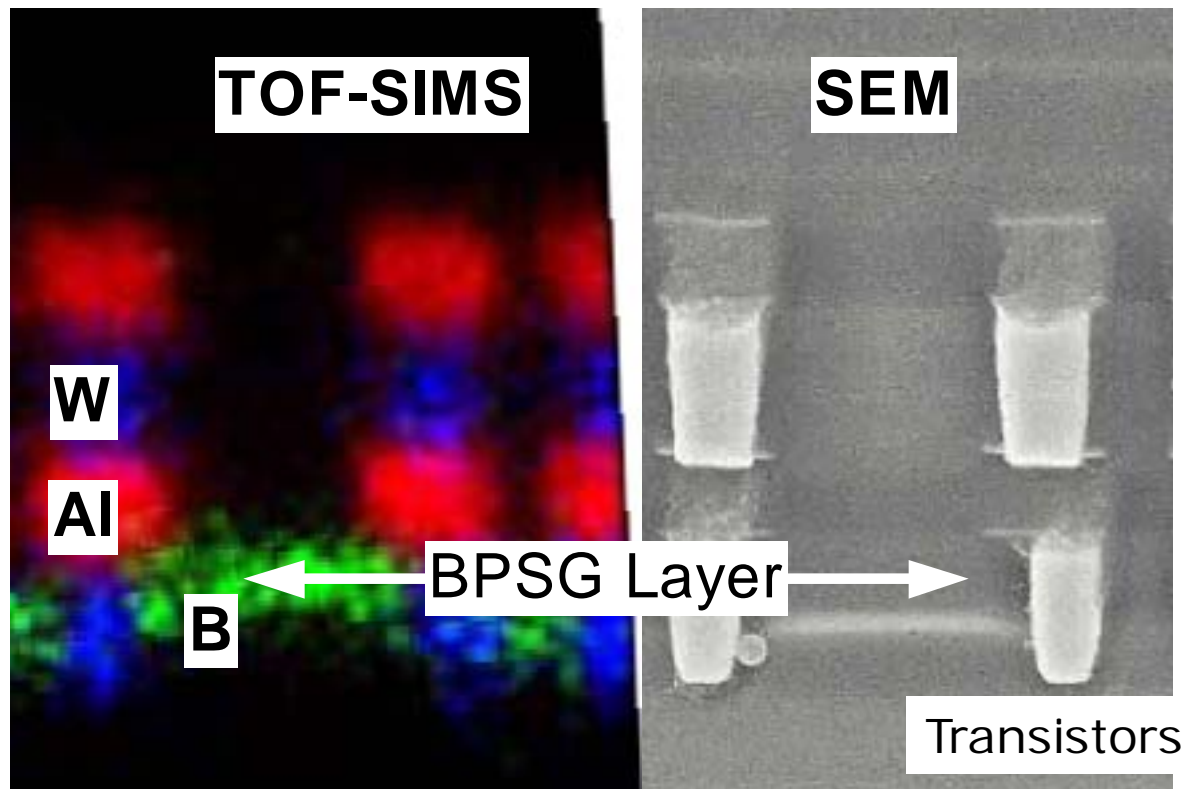
---

- ❑ JESD89A – JEDEC standard for soft-error testing.
- ❑ [www.seutest.com](http://www.seutest.com) – JESD89A soft-error testing resources

# What's so special about boron?

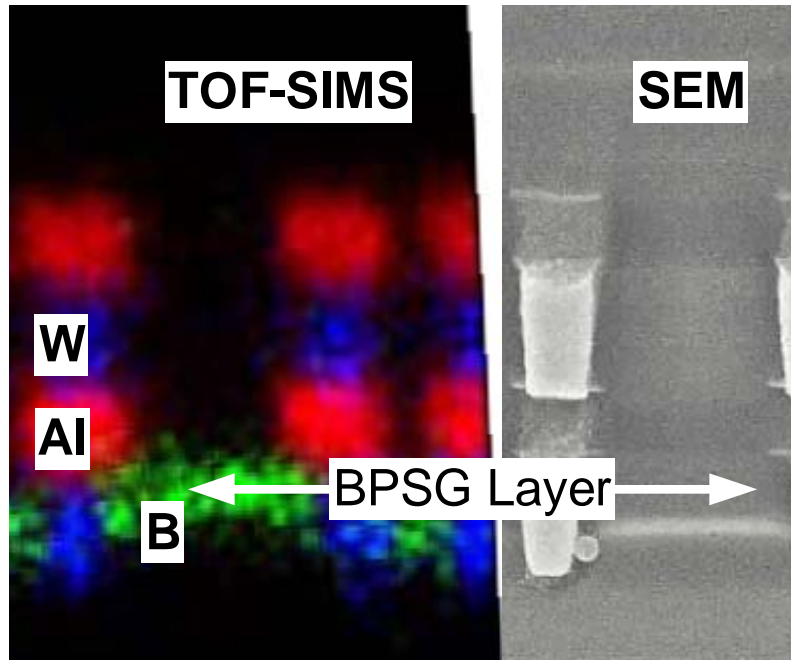


# Typical IC cross section



*Wilkinson et al, 2005*

# BPSG and thermal neutrons are still problems for end users.



BPSG is still found in commonly available ICs.



Thermal neutron environment near cancer radiotherapy is  $40 \times 10^6$  X accelerated, leading to severe problems for medical devices



# TOF-SIMS results for commercial ICs

---

